

Hidetaka Sawada

List of Publications by Year in descending order

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Version: 2024-02-01

40
papers

1,365
citations

394421

19
h-index

395702

33
g-index

40
all docs

40
docs citations

40
times ranked

1654
citing authors

#	ARTICLE	IF	CITATIONS
1	Direct imaging of hydrogen-atom columns in a crystal by annular bright-field electron microscopy. <i>Nature Materials</i> , 2011, 10, 278-281.	27.5	313
2	Visualizing and identifying single atoms using electron energy-loss spectroscopy with low accelerating voltage. <i>Nature Chemistry</i> , 2009, 1, 415-418.	13.6	152
3	STEM imaging of 47-pm-separated atomic columns by a spherical aberration-corrected electron microscope with a 300-kV cold field emission gun. <i>Journal of Electron Microscopy</i> , 2009, 58, 357-361.	0.9	147
4	Performance of low-voltage STEM/TEM with delta corrector and cold field emission gun. <i>Journal of Electron Microscopy</i> , 2010, 59, S7-S13.	0.9	98
5	Direct imaging of lithium atoms in LiV ₂ O ₄ by spherical aberration-corrected electron microscopy. <i>Microscopy (Oxford, England)</i> , 2010, 59, 457-461.	1.5	76
6	Achieving 63 pm Resolution in Scanning Transmission Electron Microscope with Spherical Aberration Corrector. <i>Japanese Journal of Applied Physics</i> , 2007, 46, L568-L570.	1.5	62
7	Development of Cs and Cc correctors for transmission electron microscopy. <i>Microscopy (Oxford, England)</i> , 2015, 64, 213-217.	1.5	54
8	Attainment of 40.5 pm spatial resolution using 300 kV scanning transmission electron microscope equipped with fifth-order aberration corrector. <i>Microscopy (Oxford, England)</i> , 2018, 67, 46-50.	1.5	51
9	Atomic Resolution Defocused Electron Ptychography at Low Dose with a Fast, Direct Electron Detector. <i>Scientific Reports</i> , 2019, 9, 3919.	3.3	44
10	Resolving 45-pm-separated Si-Si atomic columns with an aberration-corrected STEM. <i>Microscopy (Oxford, England)</i> , 2015, 64, 213-217.	1.5	38
11	Counting lithium ions in the diffusion channel of an LiV ₂ O ₄ crystal. <i>Journal of Applied Physics</i> , 2011, 109, .	2.5	34
12	Quantitative annular dark-field STEM images of a silicon crystal using a large-angle convergent electron probe with a 300-kV cold field-emission gun. <i>Journal of Electron Microscopy</i> , 2011, 60, 109-116.	0.9	30
13	Resolution enhancement in transmission electron microscopy with 60-kV monochromated electron source. <i>Applied Physics Letters</i> , 2016, 108, 013107.	3.3	29
14	Hollow Electron Ptychographic Diffractive Imaging. <i>Physical Review Letters</i> , 2018, 121, 146101.	7.8	27
15	Atomic Structure Imaging Beyond Conventional Resolution Limits in the Transmission Electron Microscope. <i>Physical Review Letters</i> , 2009, 103, 126101.	7.8	26
16	Evaluation of residual aberration in fifth-order geometrical aberration correctors. <i>Microscopy (Oxford, England)</i> , 2018, 67, 156-163.	1.5	23
17	First experiments of selected area nano-diffraction from semiconductor interfaces using a spherical aberration corrected TEM. <i>Microscopy (Oxford, England)</i> , 2005, 54, 123-126.	1.5	22
18	Atomic Resolution Imaging at an Ultralow Accelerating Voltage by a Monochromatic Transmission Electron Microscope. <i>Physical Review Letters</i> , 2016, 117, 153004.	7.8	22

#	ARTICLE	IF	CITATIONS
19	Imaging the Active Surfaces of Cerium Dioxide Nanoparticles. <i>ChemPhysChem</i> , 2011, 12, 2397-2399.	2.1	20
20	Imaging of a single atomic column in silicon grain boundary. <i>Journal of Electron Microscopy</i> , 2002, 51, 353-357.	0.9	14
21	Evaluation of probe size in STEM imaging at 30 and 60kV. <i>Micron</i> , 2012, 43, 551-556.	2.2	14
22	Atomic structure of the $\hat{1}\hat{1}\hat{3}$ and $\hat{1}\hat{1}\hat{9}$ grain boundaries in CVD diamond film. <i>Scripta Materialia</i> , 2004, 51, 689-692.	5.2	12
23	Aberration Correctors Developed Under the Triple C Project. <i>Advances in Imaging and Electron Physics</i> , 2011, 168, 297-336.	0.2	12
24	Resolution enhancement at a large convergence angle by a delta corrector with a CFEG in a low-accelerating-voltage STEM. <i>Micron</i> , 2014, 63, 35-39.	2.2	8
25	Exceeding Conventional Resolution Limits in High-Resolution Transmission Electron Microscopy Using Tilted Illumination and Exit-Wave Restoration. <i>Microscopy and Microanalysis</i> , 2010, 16, 409-415.	0.4	7
26	Resolution Achievement of 40.5 pm in Scanning Transmission Electron Microscopy using 300 kV Microscope with Delta Corrector. <i>Microscopy and Microanalysis</i> , 2018, 24, 120-121.	0.4	6
27	Determination of aberration center of Ronchigram for automated aberration correctors in scanning transmission electron microscopy. <i>Ultramicroscopy</i> , 2013, 135, 71-79.	1.9	5
28	Image transfer with spatial coherence for aberration corrected transmission electron microscopes. <i>Ultramicroscopy</i> , 2016, 167, 11-20.	1.9	5
29	Aberration measurement of the probe-forming system of an electron microscope using two-dimensional materials. <i>Ultramicroscopy</i> , 2017, 182, 195-204.	1.9	5
30	Fast and Low-dose Electron Ptychography. <i>Microscopy and Microanalysis</i> , 2018, 24, 224-225.	0.4	3
31	Element discrimination in a hexagonal boron nitride nanosheet by aberration corrected transmission electron microscopy. <i>Ultramicroscopy</i> , 2012, 122, 6-11.	1.9	2
32	Innovative electron microscope for light-element atom visualization. <i>Synthesiology</i> , 2012, 4, 172-182.	0.2	2
33	Corrosion of Gold by a Nanoscale Gold and Copper Beltlike Structure. <i>Journal of Physical Chemistry C</i> , 2019, 123, 19920-19926.	3.1	2
34	Surface Modification of Cubic Gan Buffer Layer Grown by Metalorganic Vapor Phase Epitaxy. <i>Materials Research Society Symposia Proceedings</i> , 2000, 639, 3201.	0.1	0
35	Characterization of thin film displacements in the electron microscope. <i>Applied Physics Letters</i> , 2017, 111, 203104.	3.3	0
36	STEM and Elemental Analysis by EDS and EELS for Two-dimensional Atomic Structure Containing Au and Cu. <i>Microscopy and Microanalysis</i> , 2019, 25, 1776-1777.	0.4	0

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37	HRTEM Image of a Diamond; metal Interface. <i>Materia Japan</i> , 2001, 40, 1030-1030.	0.1	0
38	Grain Boundary Structure Analysis of Covalent Bonding Materials by Atomic Resolution Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2001, 7, 276-277.	0.4	0
39	Visualization of Light Elements using Annular Bright Field Imaging with a Cs-corrected Scanning Transmission Electron Microscope. <i>Journal of the Vacuum Society of Japan</i> , 2011, 54, 248-252.	0.3	0
40	Innovative electron microscope for light-element atom visualization. <i>Synthesiology</i> , 2011, 4, 166-175.	0.2	0